

Search Notes

Application/Control No.

10/791,751

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

TOMITA ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	774 - 776, 758 and 700	1/31/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGUPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	1/31/2006	C.C.